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(54) **INTEGRATED CIRCUIT DEVICE CHARACTERIZATION**

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(57) **ABSTRACT**

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One or more electrical characteristics of an integrated circuit device are measured at one or more relatively lower frequencies. One or more parameters of the integrated circuit device are measured at one or more frequencies higher than the one or more relatively lower frequencies. One or more parameters of the integrated circuit device are calculated based on the measured one or more electrical characteristics. The integrated circuit device is characterized based on the calculated one or more parameters and the measured one or more parameters.

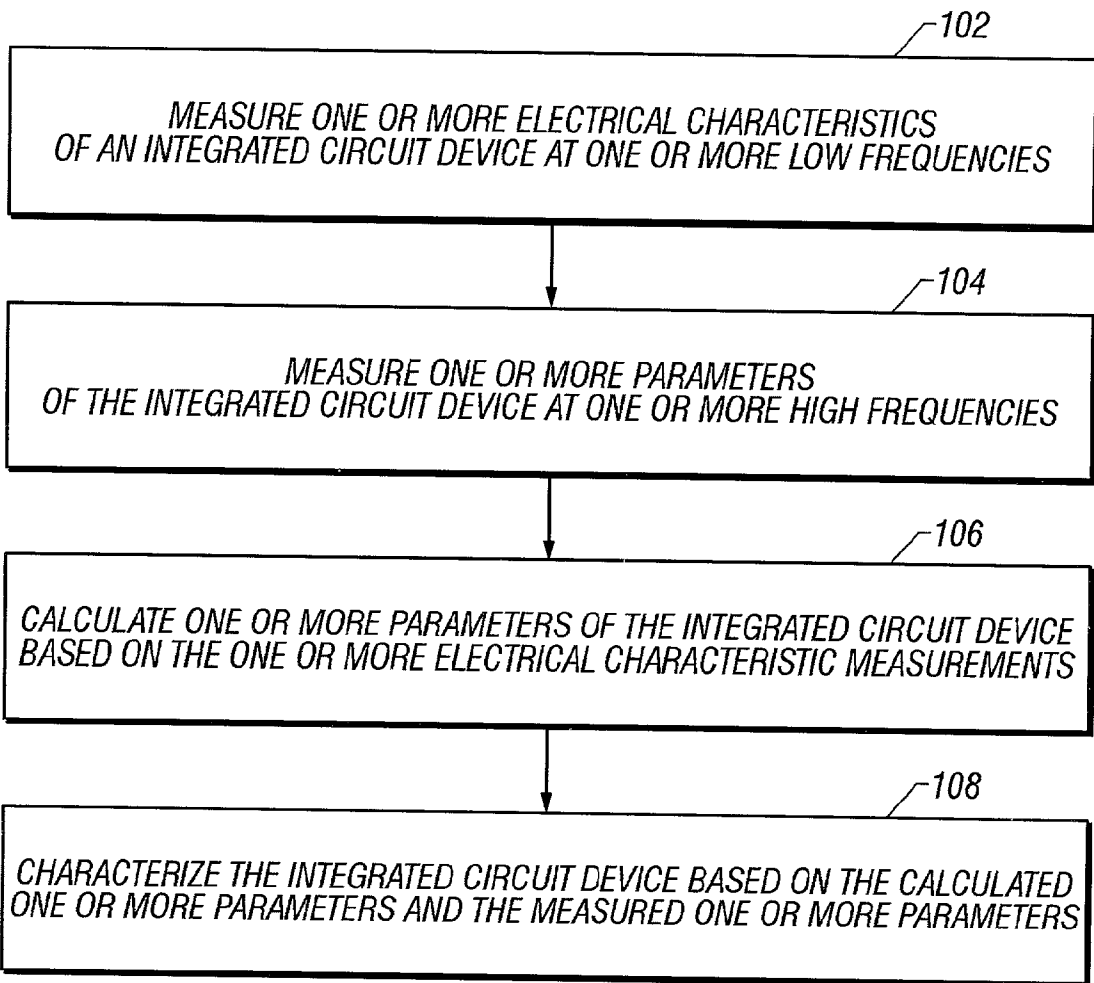
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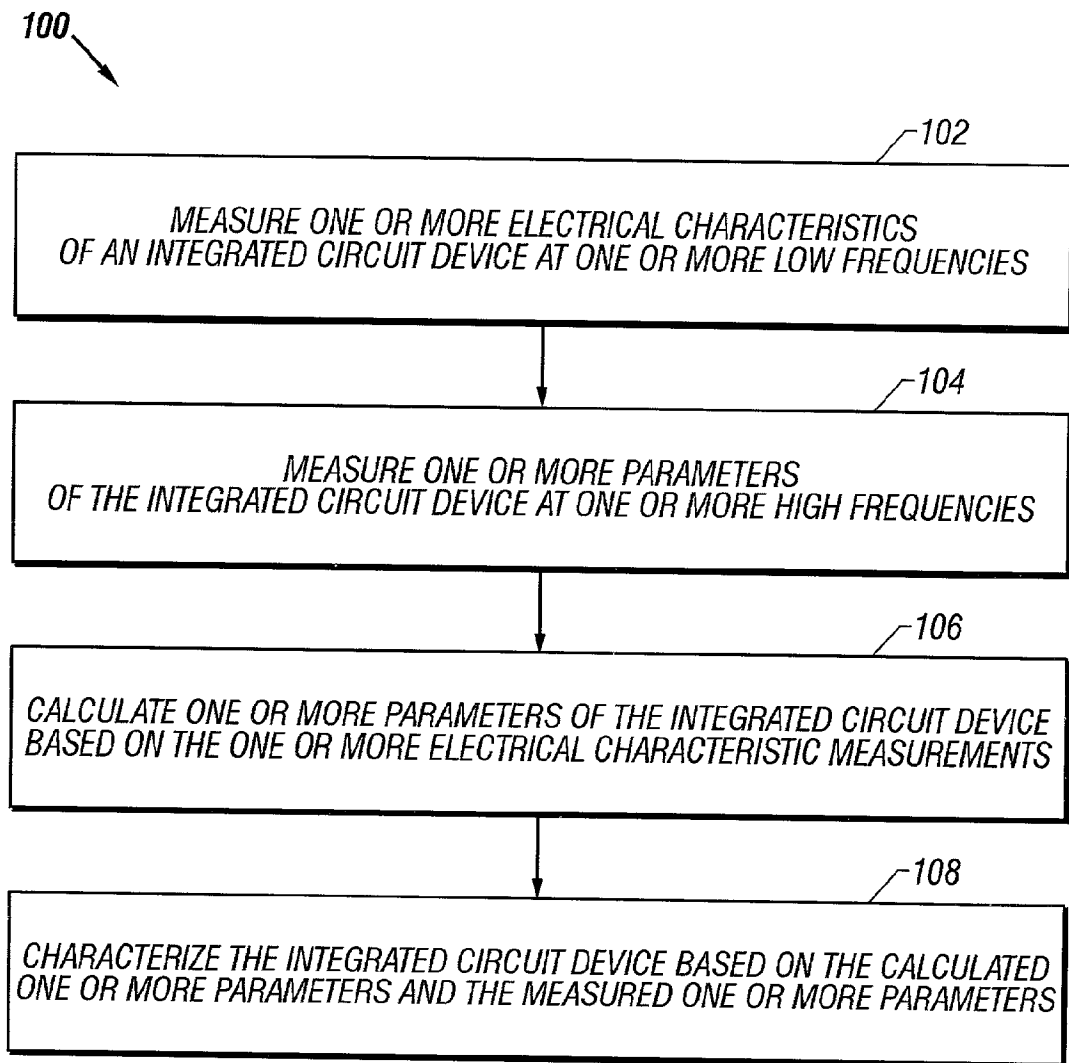


FIG. 1

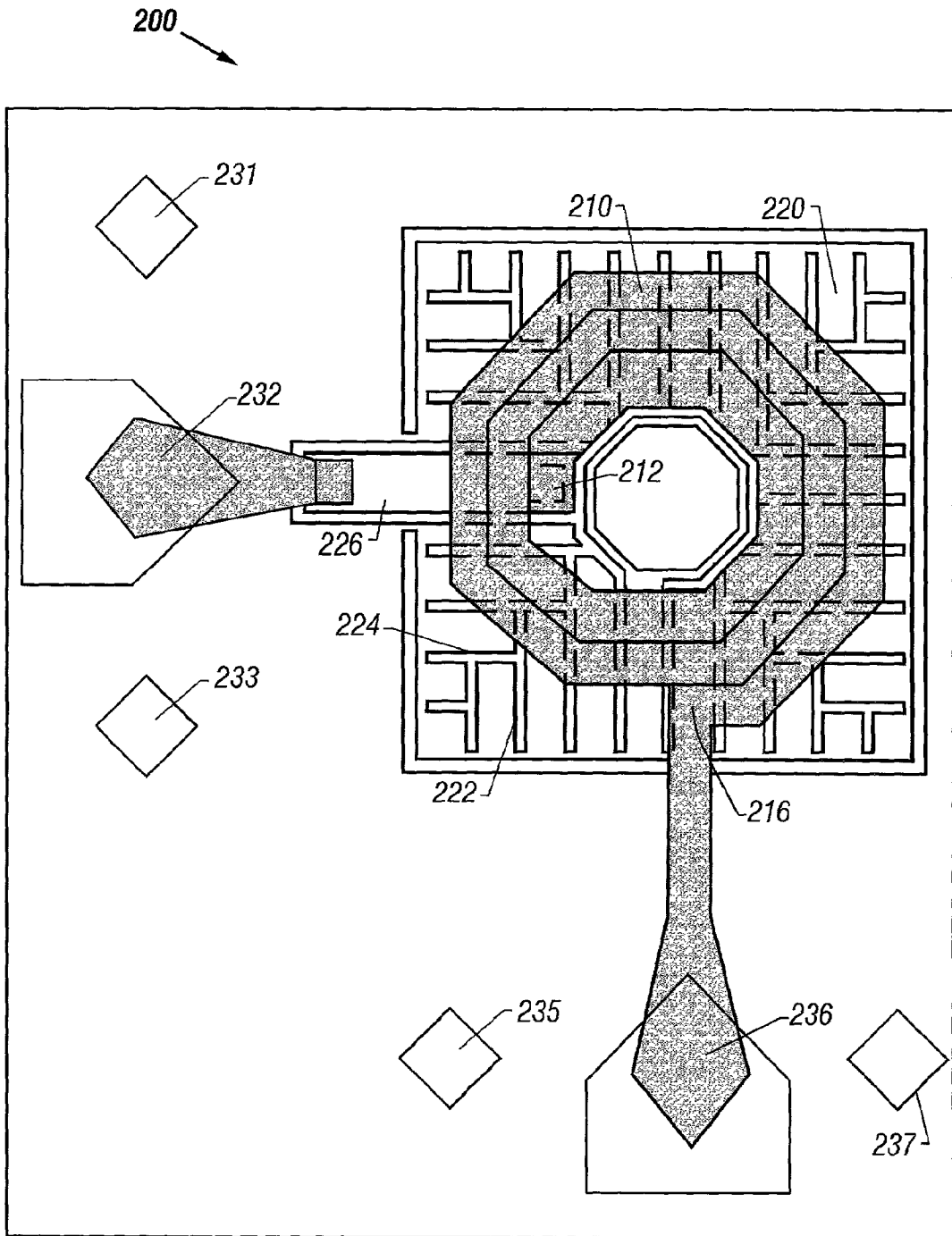


FIG. 2

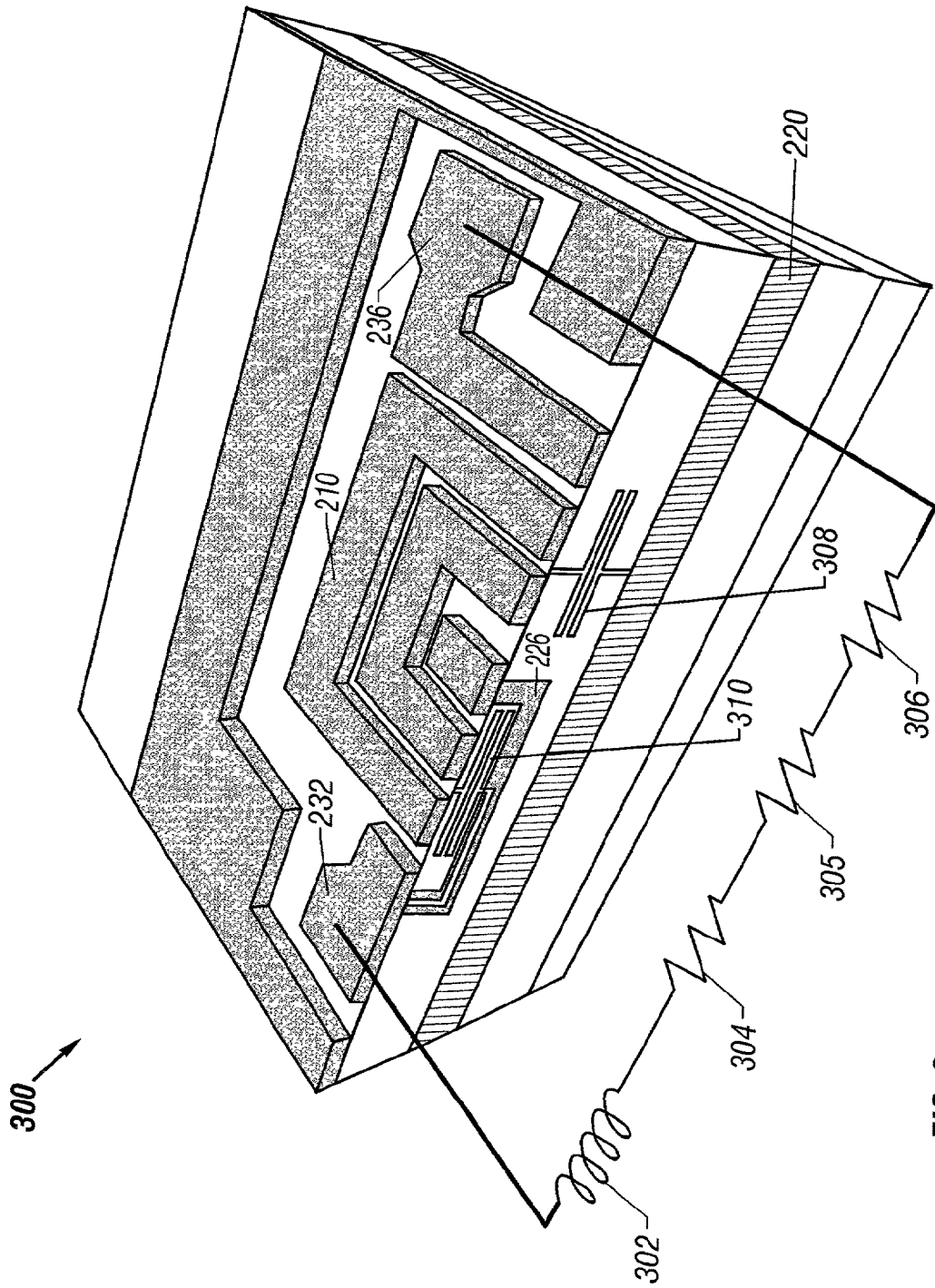


FIG. 3

400 ↘

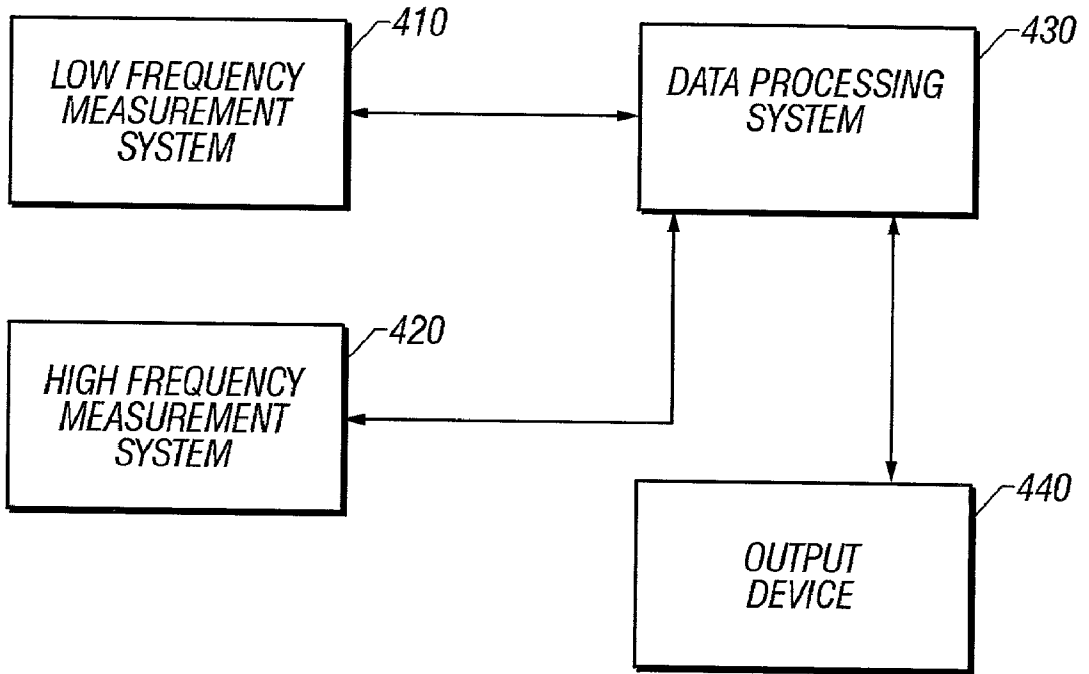


FIG. 4

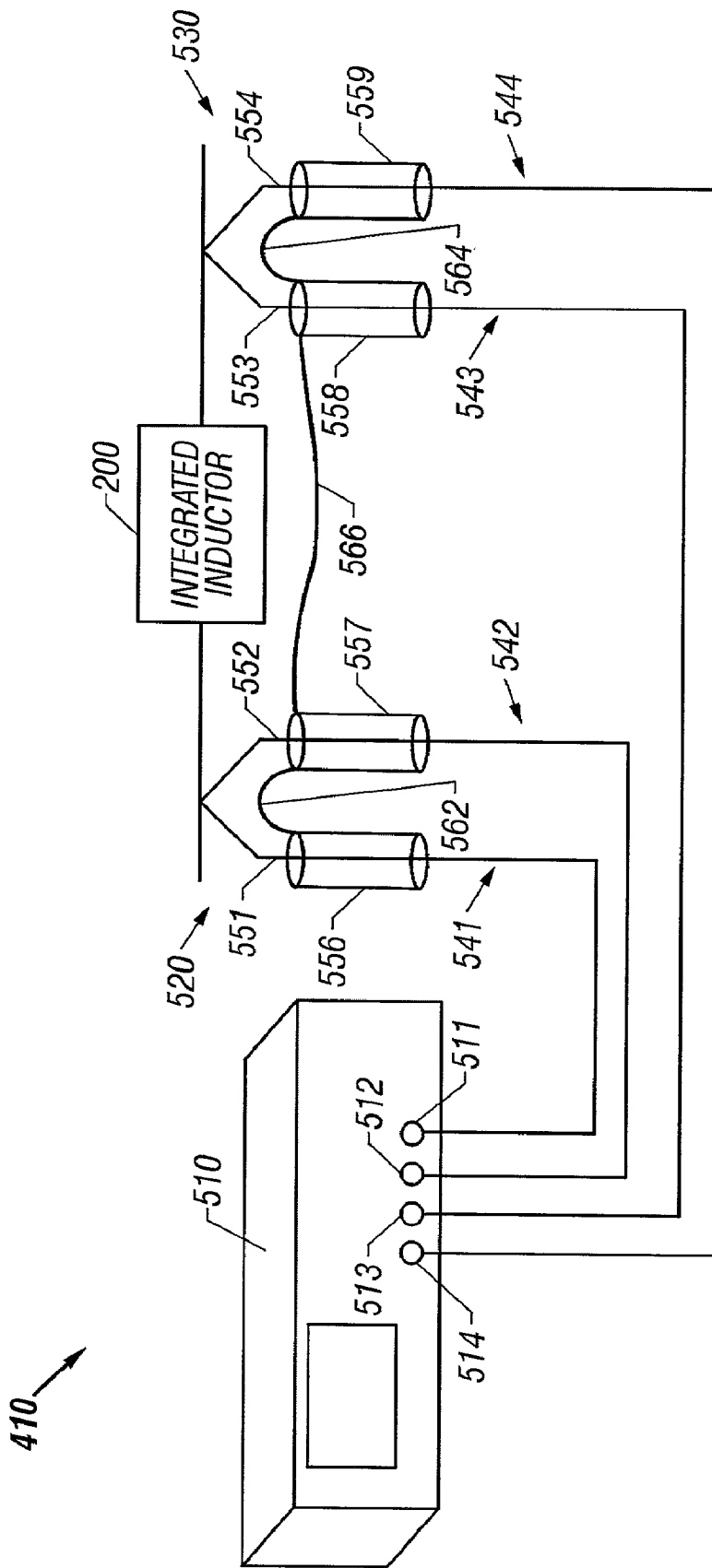


FIG. 5

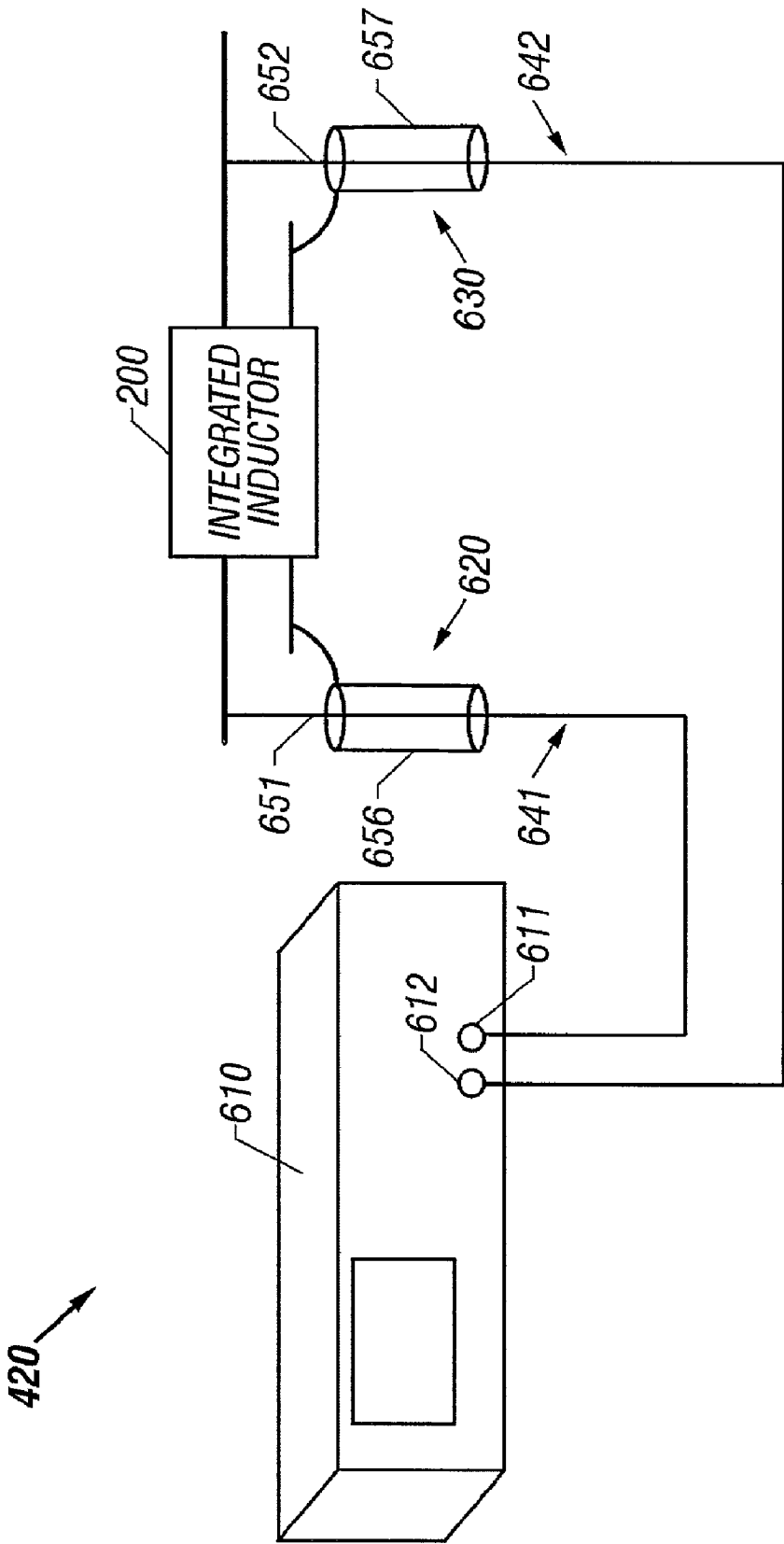


FIG. 6

INTEGRATED CIRCUIT DEVICE CHARACTERIZATION

BACKGROUND OF THE INVENTION

[0001] 1. Field of the Invention

[0002] The present invention relates generally to the field of circuit characterization. More particularly, the present invention relates to the field of integrated circuit device characterization.

[0003] 2. Description of Related Art

[0004] Integrated radio frequency (RE) circuit devices may be measured using network analyzers that typically operate from approximately 0.1 GigaHertz (GHz) to approximately 20 GHz. As the sensitivity of a typical network analyzer is limited to no less than several ohms of reactance, integrated circuit devices that are to operate at relatively low frequencies and/or with electrical characteristics having relatively low values may not be measured using network analyzers.

[0005] As one example, an integrated inductor that has an inductance below 100 nanoHenries (nH) and that is to operate at a frequency of approximately 3 MegaHertz (MHz) could not be measured by a typical network analyzer even if the network analyzer could be operated at a relatively lower frequency such as approximately 1 MHz, for example. As another example, inductors comprising a magnetic material such as a nickel iron (NiFe) permalloy, for example, cannot be measured by a typical network analyzer because such inductors can only be operated at relatively low frequencies below 100 MHz, for example. The magnetic material otherwise becomes lossy.

[0006] Characterizing an integrated RF circuit device such as an inductor, for example, at relatively high frequencies with a network analyzer is challenging. The cross-sectional area of the conductor for the inductor becomes reduced due to skin effects, thereby increasing the resistance of the inductor. Parasitic capacitances and resistances in the substrate of the integrated RF circuit device depend on the frequency at which the integrated RF circuit device operates. Also, parasitics exist in the cables and probes of the network analyzer.

BRIEF DESCRIPTION OF THE DRAWINGS

[0007] The present invention is illustrated by way of example and not limitation in the Figures of the accompanying drawings, in which like references indicate similar elements and in which:

[0008] FIG. 1 illustrates, for one embodiment, a flow diagram to characterize an integrated circuit device;

[0009] FIG. 2 illustrates, for one embodiment, an integrated inductor;

[0010] FIG. 3 illustrates, for one embodiment, an electrical model for the integrated inductor of FIG. 2;

[0011] FIG. 4 illustrates, for one embodiment, a system to characterize an integrated circuit device;

[0012] FIG. 5 illustrates, for one embodiment, a relatively lower frequency measurement system; and

[0013] FIG. 6 illustrates, for one embodiment, a relatively higher frequency measurement system.

DETAILED DESCRIPTION

[0014] The following detailed description sets forth an embodiment or embodiments in accordance with the present invention for integrated circuit device characterization. In the following description, details are set forth such as a specific circuit model, measurement equipment, etc. in order to provide a thorough understanding of the present invention. It will be evident, however, that the present invention may be practiced without these details. In other instances, well-known algorithms, etc. have not been described in particular detail so as not to obscure the present invention.

[0015] FIG. 1 illustrates, for one embodiment, a flow diagram 100 to characterize an integrated circuit device, such as an integrated inductor 200 as illustrated in FIG. 2. Although described in the context of integrated inductor 200, any suitable integrated circuit device including any other suitable integrated inductor may be characterized in accordance with flow diagram 100.

[0016] As illustrated in FIG. 2, integrated inductor 200 comprises a generally spiral-shaped conductor 210 defining a signal path along which current may flow to generate an electromagnetic field around conductor 210. Current may flow through conductor 210 by applying a voltage potential across an innermost node 212 near the beginning of the innermost turn of conductor 210 and an outermost node 216 near the end of the outermost turn of conductor 210. Node 212 is coupled to a pad 232 by a conductive underpass 226 that passes under each turn of conductor 210 and that is separated from conductor 210 by a dielectric layer. Node 216 is coupled to a pad 236. Integrated inductor 200 for one embodiment also comprises pads 231, 233, 235, and 237 each coupled to a ground node. Although described in the context of a ground node, the node coupled to each pad 231, 233, 235, and 237 may have any suitable voltage potential.

[0017] Integrated inductor 200 for one embodiment comprises an optional magnetic layer 220. Conductor 210 is positioned over magnetic layer 220 and is separated from magnetic layer 220 by at least a dielectric layer. Magnetic layer 220 forms a reference voltage plane for integrated inductor 200 to help contain electric and magnetic fields around conductor 210. Magnetic layer 220 for one embodiment is patterned to define conductive underpass 226.

[0018] Integrated inductor 200 for one embodiment is formed over a substrate comprising a semiconductor material with at least a dielectric layer separating magnetic layer 220 from the substrate. As conductor 210 generates a magnetic flux toward the substrate that would induce Eddy or mirror currents and noise in the substrate, positioning magnetic layer 220 between the substrate and conductor 210 helps reduce such currents and therefore helps reduce losses in integrated inductor 200 and minimizes concern for interference between integrated inductor 200 and neighboring circuitry. Magnetic layer 220 also helps prevent substrate coupling and helps reduce substrate dependency.

[0019] Integrated inductor 200 may be designed to have a suitable quality factor Q. The quality factor Q is proportional to $\omega L/R$, where ω is the operating frequency for integrated inductor 200, L is the inductance of integrated inductor 200,

and R is the resistance of integrated inductor **200**. As the quality factor Q of integrated inductor **200** is proportional to the inductance L of integrated inductor **200** and inversely proportional to the resistance R of integrated inductor **200**, integrated inductor **200** can be designed with a relatively higher inductance L , and therefore a relatively higher quality factor Q , for a given area or resistance R of integrated inductor **200**. Alternatively, for a given inductance L , integrated inductor **200** can be designed with a relatively smaller area and therefore a relatively lower resistance R and capacitance, resulting in a relatively higher resonance frequency ω_r and a relatively higher quality factor Q for integrated inductor **200**.

[0020] Factors influencing the quality factor Q for integrated inductor **200** include the amount of area covered by conductor **210**, the number of turns of conductor **210**, the shape of each turn, the conductive material used for conductor **210**, the width, thickness, and length of conductor **210**, and the amount of spacing between turns for conductor **210**.

[0021] Using magnetic layer **220** also helps influence the quality factor Q for integrated inductor **200**. Magnetic layer **220** helps increase the inductance L of integrated inductor **200**, and therefore the quality factor Q for integrated inductor **200**. The magnetic material and thickness of magnetic layer **220** help determine the frequency at which integrated inductor **200** may be operated and the inductance L of integrated inductor **200**. Magnetic layer **220** for one embodiment comprises a cobalt-zirconium-tantalum (CoZrTa) alloy that can operate in the GigaHertz (GHz) range. The dielectric material and thickness for the dielectric layer between conductor **210** and magnetic layer **220** help determine the capacitance and therefore the resonance frequency ω_r for integrated inductor **200**. Defining optional slots in magnetic layer **220**, such as slots **222** and **224** for example, helps reduce Eddy currents in magnetic layer **220** and helps increase the resonance frequency ω_r for integrated inductor **200**.

[0022] FIG. 3 illustrates an exemplary electrical model **300** of integrated inductor **200**. Electrical model **300** represents one or more electrical characteristics of integrated inductor **200** with corresponding ideal circuit elements and is used to help characterize integrated inductor **200**. Electrical model **300** for one embodiment is an equivalent circuit model of integrated inductor **200**.

[0023] Electrical model **300** for one embodiment comprises an inductor **302** representing the inductance L of the integrated inductor **200**, a resistor **304** representing the resistance R of the integrated inductor **200**, a resistor **305** representing a resistance R_{se} caused by skin effect in integrated inductor **200**, a resistor **306** representing a resistance R_{Eddy} caused by Eddy current losses in magnetic layer **220** and the substrate, a capacitor **308** representing a capacitance C_{c-m} between conductor **210** and magnetic layer **220**, and a capacitor **310** representing a capacitance C_{c-u} between conductor **210** and conductive underpass **226**. Other equivalent circuit models mathematically related to electrical model **300** of FIG. 3 may be used for other embodiments.

[0024] The characterization of integrated inductor **200** in accordance with flow diagram **100** of FIG. 1 may be performed using any suitable equipment. For one embodiment, an integrated circuit device characterization system

400 as illustrated in FIG. 4 may be used to characterize an integrated circuit device. Integrated circuit device characterization system **400** for one embodiment comprises a low frequency measurement system **410**, a high frequency measurement system **420**, a data processing system **430**, and an output device **440**.

[0025] For block **102** of FIG. 1, one or more electrical characteristics of integrated inductor **200** are measured at one or more relatively lower frequencies. Any suitable electrical characteristics may be measured at any suitable one or more frequencies using any suitable measuring equipment. For one embodiment, electrical characteristics may be measured in the range from approximately 10 kiloHertz (kHz) to approximately 100 MegaHertz (MHz).

[0026] For one embodiment, low frequency measurement system **410** of FIG. 4 is used to measure one or more electrical characteristics of integrated inductor **200**. Measurement system **410** for one embodiment, as illustrated in FIG. 5, comprises an impedance analyzer **510**, a first probe **520**, and a second probe **530**. Impedance analyzer **510** for one embodiment is manufactured by Agilent Technologies, Inc. of Palo Alto, Calif. under model number 4294A and can measure electrical characteristics at frequencies ranging from approximately 40 Hertz (Hz) to approximately 110 MegaHertz (MHz). Probes **520** and **530** may each comprise any suitable probe. Each probe **520** and **530** for one embodiment comprises a Picoprobe® dual microwave probe manufactured by GGB Industries, Inc. of Naples, Fla.

[0027] Probes **520** and **530** for one embodiment are coupled to impedance analyzer **510** using a four-terminal configuration. A relatively high current terminal **511** and a relatively high voltage potential terminal **512** are coupled to probe **520** by respective lines **541** and **542**. A relatively low voltage potential terminal **513** and a relatively low current terminal **514** are coupled to probe **530** by respective lines **543** and **544**. Probe **520** may be conductively coupled to either pad **232** or **236**, and probe **530** may be conductively coupled to the other pad **232** or **236** to measure one or more electrical characteristics of integrated inductor **200**.

[0028] Lines **541**, **542**, **543**, and **544** for one embodiment each comprise a coaxial cable each having an inner wire **551**, **552**, **553**, and **554**, respectively, surrounded by a shield **556**, **557**, **558**, and **559**, respectively. Inner wires **551** and **552** may be conductively coupled to either pad **232** or **236** and inner wires **553** and **554** may be conductively coupled to the other pad **232** or **236** to measure one or more electrical characteristics of integrated inductor **200**.

[0029] Each shield **556**, **557**, **558**, and **559** for one embodiment is driven by impedance analyzer **510** at a voltage that varies as a function of frequency to compensate for the impedance of the coaxial cables. Each shield **556**, **557**, **558**, and **559** is then to remain electrically isolated from ground and from any body of corresponding probe **520** or **530**. For one embodiment, shields **556**, **557**, **558**, and **559** each extend to a location at or near the tip of corresponding probe **520** or **530**. Shields **556**, **557**, **558**, and **559** may then be conductively coupled to one another at or near integrated inductor **200** to help obtain increased measurement sensitivity. As one example, inductance values below one nanoHenry (nH) at frequencies in the MegaHertz range (MHz) may be measured.

[0030] Shields **556**, **557**, **558**, and **559** may be conductively coupled to one another in any suitable manner. For

one embodiment, shields **556** and **557** may be conductively coupled to one another at or near the end of each shield **556** and **557** using a foil jumper **562**, for example, and shields **558** and **559** may be conductively coupled to one another at or near the end of each shield **558** and **559** using a foil jumper **564**, for example. A foil jumper or braid **566** may be soldered at or near the end of each shield **557** and **558**, for example, to conductively couple shields **556** and **557** to shields **558** and **559**. Foil jumper or braid **566** for one embodiment may comprise two pieces, each soldered to a separate shield, that are then connected together after probes **520** and **530** are positioned to measure integrated inductor **200**, for example.

[0031] Impedance analyzer **510** for one embodiment is calibrated with an open-short-load calibration technique across the tip of each probe **520** and **530**. While impedance analyzer **510** is calibrated, shields **556**, **557**, **558**, and **559** are to remain electrically isolated from any calibration substrate as impedance analyzer **510** may then drive a contacted portion of the calibration substrate. Any measurements made with impedance analyzer **510** may then be inaccurate. Shields **556**, **557**, **558**, and **559** are similarly to remain electrically isolated from integrated inductor **200** while impedance analyzer **510** is used to measure integrated inductor **200**.

[0032] Measurement system **410** for one embodiment is used to measure one or more circuit element values of electrical model **300** for integrated inductor **200**. Values for inductor **302** and capacitor **308**, for example, may be measured. As any increase resistance from skin effects and Eddy currents is minimal at relatively low frequencies, a value for resistor **304** may also be measured.

[0033] For block **104** of FIG. 1, one or more parameters of integrated inductor **200** are measured at one or more relatively high frequencies. Any suitable parameters may be measured at any suitable one or more frequencies using any suitable measuring equipment. For one embodiment, parameters may be measured in the range from approximately 30 MegaHertz (MHz) to approximately 20 GigaHertz (GHz).

[0034] For one embodiment, high frequency measurement system **420** of FIG. 4 is used to measure one or more parameters of integrated inductor **200**. Measurement system **420** for one embodiment, as illustrated in FIG. 6, comprises a network analyzer **610**, a first probe **620**, and a second probe **630**. Network analyzer **610** for one embodiment is manufactured by Agilent Technologies, Inc. of Palo Alto, Calif. under model number 8720D and can measure parameters of integrated inductor **200** at frequencies ranging from approximately 0.05 GigaHertz (GHz) to approximately 20 GHz. Probes **620** and **630** may each comprise any suitable probe. Each probe **620** and **630** for one embodiment comprises a microwave probe manufactured by GGB Industries, Inc. of Naples, Fla. under model number 40A.

[0035] Network analyzer **610** for one embodiment measures integrated inductor **200** at a first port between pad **232** and pads **231** and/or **233** and at a second port between pad **236** and pads **235** and/or **237**.

[0036] Probes **620** and **630** for one embodiment are coupled to network analyzer **610** using a two-terminal configuration. A terminal **611** is coupled to probe **620** by a line **641**. A terminal **612** is coupled to probe **630** by a line

642. Probe **620** may be conductively coupled to either the first or second port of integrated inductor **200**, and probe **630** may be conductively coupled to the other port of integrated inductor **200** to measure one or more parameters of integrated inductor **200**. Probes **620** and **630** for one embodiment each has a ground-signal-ground (GSG) footprint to couple to pads **231-233** and pads **235-237**. For another embodiment, each probe **620** and **630** may have a ground-signal (GS) footprint and use only one pad **231** or **233** with pad **232** and only one pad **235** or **237** with pad **236**.

[0037] Lines **641** and **642** for one embodiment each comprise a coaxial cable each having an inner wire **651** and **652**, respectively, surrounded by a shield **656** and **657**, respectively. Inner wire **651** may be conductively coupled to either pad **232** or **236** and inner wire **652** may be conductively coupled to the other pad **232** or **236** to measure one or more parameters of integrated inductor **200**. Shield **656** may be conductively coupled to pads **231** and/or **233** when inner wire **651** is to be conductively coupled to pad **232**. Shield **656** may be conductively coupled to pads **235** and/or **237** when inner wire **651** is to be conductively coupled to pad **236**. Shield **657** may be conductively coupled to pads **231** and/or **233** when inner wire **652** is to be conductively coupled to pad **232**. Shield **657** may be conductively coupled to pads **235** and/or **237** when inner wire **652** is to be conductively coupled to pad **236**.

[0038] Network analyzer **610** for one embodiment is calibrated with an open-short-load calibration technique between the signal tip and ground node for each probe **620** and **630** and with a through calibration technique across the signal tips and ground nodes for each probe **620** and **630**.

[0039] For one embodiment, scattering parameters (s-parameters) of integrated inductor **200** may be measured. S-parameters are power wave descriptors that allow the input-output relations of a network to be defined in terms of incident, transmitted, and reflected power waves. S-parameters may therefore be used to describe how a circuit behaves.

[0040] Power waves can be fed into and taken from each port of integrated inductor **200**. An incident power wave applied to one port can be partially reflected by integrated inductor **200** to form a reflected power wave at that port and partially transmitted through integrated inductor **200** to form a transmitted power wave at the other port.

[0041] The incident normalized power waves for the first and second ports may be represented by complex quantities a_1 and a_2 , respectively, and the transmitted or reflected normalized power waves for the first and second ports may be represented by complex quantities b_1 and b_2 , respectively. The transmitted or reflected waves may be expressed in terms of the incident waves by the matrix equation $B=S \times A$, where B is a vector containing b_1 and b_2 , A is a vector containing a_1 and a_2 , and S is a 2×2 square matrix of s parameters s_{11} , s_{12} , s_{21} , and s_{22} .

[0042] The s-parameters s_{11} , s_{12} , s_{21} , and s_{22} for integrated inductor **200** therefore satisfy the following equations:

$$\begin{aligned} b_1 &= s_{11} \times a_1 + s_{12} \times a_2 \\ b_2 &= s_{21} \times a_1 + s_{22} \times a_2 \\ a_1 &= (V_1 + Z_0 \times I_1) / (2 \times Z_0^{1/2}) \\ a_2 &= (V_2 + Z_0 \times I_2) / (2 \times Z_0^{1/2}) \end{aligned}$$

$$b_1=(V_1-Z_0I_1)/(2\times Z_0^{1/2})$$

$$b_2=(V_2-Z_0I_2)/(2\times Z_0^{1/2})$$

[0043] where V_1 represents a voltage at the first port of integrated inductor **200**, I_1 represents a current at the first port of integrated inductor **200**, V_2 represents a voltage at the second port of integrated inductor **200**, I_2 represents a current at the second port of integrated inductor **200**, and Z_0 represents the characteristic impedance of the connecting lines at the first and second ports of integrated inductor **200**.

[0044] Each s-parameter s_{11} , s_{12} , s_{21} , and s_{22} is frequency-dependent and has a real and imaginary part. They can also be converted to a magnitude and phase angle.

[0045] Where no power waves are applied to the second port, that is when $a_2=0$, the power wave incident to the first port, that is a_1 , may be partially reflected from the first port as reflected power wave $b_1=s_{11}\times a_1$ and partially transmitted out of the second port as transmitted power wave $b_2=s_{21}\times a_1$. S-parameter s_{11} then represents the ratio of the reflected power wave at the first port to the incident power wave at the first port when $a_2=0$, and s-parameter s_{21} then represents the ratio of the transmitted power wave at the second port to the incident power wave at the first port when $a_2=0$.

[0046] Where no power waves are applied to the first port, that is when $a_1=0$, the power wave incident to the second port, that is a_2 , may be partially transmitted out of the first port as transmitted power wave $b_1=s_{12}\times a_2$ and partially reflected from the second port as reflected power wave $b_2=s_{22}\times a_2$. S-parameter s_{12} then represents the ratio of the transmitted power wave at the first port to the incident power wave at the second port when $a_1=0$, and s-parameter s_{22} then represents the ratio of the reflected power wave at the second port to the incident power wave at the second port when $a_1=0$.

[0047] The conditions $a_1=0$ and $a_2=0$ imply that no power waves are applied at the first port and the second port, respectively, of integrated inductor **200**. For one embodiment, the connecting transmission lines for the first and second ports are terminated into their characteristic impedances to ensure the conditions $a_1=0$ and $a_2=0$, respectively, are satisfied.

[0048] S-parameters s_{11} and s_{21} may be measured, for example, by measuring voltage and current values at the first and second ports of integrated inductor **200** while a power wave is applied to the first port, no power waves are applied to the second port, and the second port is terminated into the lines' characteristic impedance. S-parameters s_{12} and s_{22} may be measured, for example, by measuring voltage and current values at the first and second ports of integrated inductor **200** while a power wave is applied to the second port, no power waves are applied to the first port, and the first port is terminated into the lines' characteristic impedance.

[0049] Although described as measuring one or more parameters at two ports of integrated inductor **200**, one or more parameters may be measured at another suitable number of one or more ports of the integrated circuit device to be characterized. As one example, each probe **620** and **630** for another embodiment may have only a signal footprint to measure scattering parameters of integrated inductor **200** at pads **232** and **236**.

[0050] For block **106** of FIG. 1, one or more parameters of integrated inductor **200** are calculated based on the one or more electrical characteristic measurements. Any suitable parameters may be calculated based on the one or more electrical characteristic measurements using any suitable data processing system.

[0051] For one embodiment, data processing system **430** of FIG. 4 is used to calculate one or more parameters of integrated inductor **200** based on the one or more electrical characteristic measurements. Data processing system **430** may comprise any suitable circuitry and/or devices including, for example, one or more processors to execute instructions to process data, main memory to store instructions and data that may be readily accessed by a processor, and a non-volatile memory to store software and data.

[0052] For one embodiment, low frequency measurement system **410** transmits the one or more electrical characteristic measurements to data processing system **430** over a suitable communication medium. The one or more electrical characteristic measurements for other embodiments may be manually entered into data processing system **430** or read by data processing system **430** from a suitable memory device, for example.

[0053] For one embodiment, scattering parameters (s-parameters) of integrated inductor **200** may be calculated. For one embodiment, the s-parameters s_{11} , s_{12} , s_{21} , and s_{22} for integrated inductor **200** may be calculated based on the one or more measured circuit element values for electrical model **300**. Values for resistor **304** and capacitor **308**, for example, have been measured for block **102**. An initial value for inductor **302**, for example, has also been measured for block **102**. An initial value for capacitor **310** may be theoretically calculated, for example, based on the amount of area conductive underpass **226** overlaps conductor **210**, the dielectric material between conductor **210** and conductive underpass **226**, and the thickness of the dielectric material between conductor **210** and conductive underpass **226**. Initial values for resistor **305** and **306** may be estimated. With initial values determined for each circuit element of electrical model **300**, s-parameters s_{11} , s_{12} , s_{21} , and s_{22} for integrated inductor **200** may be calculated based on the predictable behavior of electrical model **300**.

[0054] For block **108** of FIG. 1, integrated inductor **200** is characterized based on the calculated one or more parameters and the measured one or more parameters. Integrated inductor **200** may be characterized in any suitable manner using any suitable data processing system.

[0055] For one embodiment, data processing system **430** of FIG. 4 is used to characterize integrated inductor **200** based on the calculated one or more parameters and the measured one or more parameters.

[0056] For one embodiment, high frequency measurement system **420** transmits the measured one or more parameters to data processing system **430** over a suitable communication medium. The one or more measured parameters for other embodiments may be manually entered into data processing system **430** or read by data processing system **430** from a suitable memory device, for example.

[0057] For one embodiment, the calculated one or more parameters are compared to the measured one or more parameters and one or more values for electrical model **300**

are adjusted to help better fit the calculated one or more parameters to the measured one or more parameters. The one or more parameters are then recalculated based on the updated electrical model **300** and again compared to the measured one or more parameters. One or more values for electrical model **300** are iteratively adjusted in this manner until the calculated one or more parameters and the measured one or more parameters satisfy a predetermined condition. For one embodiment, one or more values for electrical model **300** are iteratively adjusted in this manner until a best fit is obtained.

[**0058**] For one embodiment, the values for resistor **304** and capacitor **308** remain fixed through the iterative updating of electrical model **300** as these values are substantially independent of frequency. The values of inductor **302**, resistor **305**, and resistor **306** are frequency dependent. The values of inductor **302**, resistor **305**, resistor **306**, and/or capacitor **310** may each be iteratively adjusted within an estimated predetermined range of values.

[**0059**] For one embodiment where the calculated and measured parameters are s-parameters, one or more values for electrical model **300** are iteratively adjusted such that the magnitude and phase angles of the ratios of each calculated s-parameter match those of the corresponding measured s-parameter. For another embodiment, one or more values for electrical model **300** are adjusted such that the magnitude of the normalized differences between the calculated s-parameters and the measured s-parameters are minimized.

[**0060**] The values for electrical model **300** obtained by fitting the calculated one or more parameters to the measured one or more parameters may be used to determine the quality factor Q, parasitic resistances and capacitances, and the inductance L of integrated inductor **200** as a function of frequency. The resonance frequency ω_r for integrated inductor **200** may also be determined.

[**0061**] Integrated inductor **200** may therefore be characterized for block **108** by the updated electrical model **300**, by any one or more determined electrical characteristics for integrated inductor **200**, and/or by the calculated one or more parameters based on the updated electrical model **300**.

[**0062**] Although described in the context of scattering parameters, other suitable parameters such as open circuit impedance parameters (z-parameters) or short circuit admittance parameters (y-parameters) for example, may also be used. Any parameters measured for block **104** and/or calculated for blocks **106** and **108** may be converted into any other suitable parameters in iteratively analyzing and updating electrical model **300**.

[**0063**] Data processing system **430** for one embodiment outputs a characterization of integrated inductor **200** to output device **440** for analysis by a user. Output device **440** may comprise a display or printer, for example. Any suitable characterization of integrated inductor **200** as determined by data processing system **430** may be output to output device **440** for display or presentation in any suitable manner.

[**0064**] In the foregoing description, the invention has been described with reference to specific exemplary embodiments thereof. It will, however, be evident that various modifications and changes may be made thereto without departing from the broader spirit or scope of the present invention as

defined in the appended claims. The specification and drawings are, accordingly, to be regarded in an illustrative rather than a restrictive sense.

What is claimed is:

1. A method comprising:

(a) measuring one or more electrical characteristics of an integrated circuit device at one or more relatively lower frequencies;

(b) measuring one or more parameters of the integrated circuit device at one or more frequencies higher than the one or more relatively lower frequencies;

(c) calculating one or more parameters of the integrated circuit device based on the measured one or more electrical characteristics; and

(d) characterizing the integrated circuit device based on the calculated one or more parameters and the measured one or more parameters.

2. The method of claim 1, wherein the measuring (a) comprises measuring one or more electrical characteristics using an impedance analyzer.

3. The method of claim 2, wherein the measuring (a) comprises driving a shield of each of a plurality of probe lines to compensate for impedance of the probe lines.

4. The method of claim 3, comprising electrically isolating each shield.

5. The method of claim 3, wherein the measuring (a) comprises conductively coupling each shield to one another at or near the integrated circuit device.

6. The method of claim 5, wherein the conductively coupling comprises coupling each shield to one another at or near an end of each shield with a foil jumper.

7. The method of claim 1, wherein the measuring (a) comprises measuring a value for one or more circuit elements of an electrical model of the integrated circuit device.

8. The method of claim 1, wherein the measuring (b) comprises measuring one or more parameters using a network analyzer.

9. The method of claim 7, wherein the calculating (c) comprises calculating one or more parameters based on the measured value for one or more circuit elements of the electrical model.

10. The method of claim 1, wherein the measuring (b) comprises measuring scattering parameters of the integrated circuit device; and

wherein the calculating (c) comprises calculating scattering parameters of the integrated circuit device.

11. The method of claim 1, wherein the characterizing (d) comprises comparing the calculated one or more parameters to the measured one or more parameters and updating one or more values for an electrical model of the integrated circuit device.

12. The method of claim 1, wherein the characterizing (d) comprises iteratively comparing the calculated one or more parameters to the measured one or more parameters, updating one or more values for an electrical model of the integrated circuit device, and recalculating the one or more parameters of the integrated circuit device based on the updated one or more values of the electrical model until the recalculated one or more parameters and the measured one or more parameters satisfy a predetermined condition.

13. An apparatus comprising:

an impedance analyzer to measure one or more electrical characteristics of an integrated circuit device at one or more relatively lower frequencies;

a network analyzer to measure one or more parameters of the integrated circuit device at one or more frequencies higher than the one or more relatively lower frequencies; and

a data processing system to calculate one or more parameters of the integrated circuit device based on the measured one or more electrical characteristics and to characterize the integrated circuit device based on the calculated one or more parameters and the measured one or more parameters.

14. The apparatus of claim 13, comprising a plurality of probes each coupled to a respective line coupled to the impedance analyzer, wherein the impedance analyzer drives a shield of each line to compensate for impedance of the line.

15. The apparatus of claim 14, wherein each shield is electrically isolated.

16. The apparatus of claim 14, wherein each shield is conductively coupled to one another at or near the integrated circuit device.

17. The apparatus of claim 16, comprising one or more foil jumpers to couple each shield to another shield at or near an end of each shield.

18. The apparatus of claim 13, wherein the impedance analyzer measures a value for one or more circuit elements of an electrical model of the integrated circuit device.

19. The apparatus of claim 18, wherein the data processing system calculates one or more parameters based on the measured value for one or more circuit elements of the electrical model.

20. The apparatus of claim 13, wherein the network analyzer measures scattering parameters of the integrated circuit device and the data processing system calculates scattering parameters of the integrated circuit device.

21. The apparatus of claim 13, wherein the data processing system compares the calculated one or more parameters to the measured one or more parameters and updates one or more values for an electrical model of the integrated circuit device.

22. The apparatus of claim 13, wherein the data processing system iteratively compares the calculated one or more parameters to the measured one or more parameters, updates one or more values for an electrical model of the integrated

circuit device, and recalculates the one or more parameters of the integrated circuit device based on the updated one or more values of the electrical model until the recalculated one or more parameters and the measured one or more parameters satisfy a predetermined condition.

23. An apparatus comprising:

(a) means for measuring one or more electrical characteristics of an integrated circuit device at one or more relatively lower frequencies;

(b) means for measuring one or more parameters of the integrated circuit device at one or more frequencies higher than the one or more relatively lower frequencies;

(c) means for calculating one or more parameters of the integrated circuit device based on the measured one or more electrical characteristics; and

(d) means for characterizing the integrated circuit device based on the calculated one or more parameters and the measured one or more parameters.

24. The apparatus of claim 23, wherein the measuring means (a) measures a value for one or more circuit elements of an electrical model of the integrated circuit device.

25. The apparatus of claim 24, wherein the calculating means (c) calculates one or more parameters based on the measured value for one or more circuit elements of the electrical model.

26. The apparatus of claim 23, wherein the measuring means (b) measures scattering parameters of the integrated circuit device and the calculating means (c) calculates scattering parameters of the integrated circuit device.

27. The apparatus of claim 23, wherein the characterizing means (d) compares the calculated one or more parameters to the measured one or more parameters and updates one or more values for an electrical model of the integrated circuit device.

28. The apparatus of claim 23, wherein the characterizing means (d) iteratively compares the calculated one or more parameters to the measured one or more parameters, updates one or more values for an electrical model of the integrated circuit device, and recalculates the one or more parameters of the integrated circuit device based on the updated one or more values of the electrical model until the recalculated one or more parameters and the measured one or more parameters satisfy a predetermined condition.

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